

ABSTRACT:

In a circuit (2) comprising a first memory means (5) for modifiable storage of information (I), the information (I) being modifiable by an ambient parameter of the circuit (2), which ambient parameter acts on the first memory means (5), there is firstly provided in the first memory means (5) a test memory area (7) for storing test information (TI) and there 5 is secondly provided a second memory means (16) for unmodifiable storage of reference information (RI) and there is thirdly provided a detection means (19), to which detection means (19) there may be supplied the test information (TI) which may be read out from the first memory means and the reference information (RI) which may be read out from the second memory means (16) and which detection means (19) is designed, with the aid of the 10 read-out test information (TI) and the read-out reference information (RI), to detect a modification of the originally stored test information (TI) brought about by an ambient parameter acting on the first memory means (5).

(Fig. 1)

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